PC	Num N	ber:	20240	)240221008.1 <b>PCN</b>			PCN Da	te:		February 21, 2024
Titl	e:	Qualification and addition							, Die	e Revision, Datasheet
Cus	tomer	Contact:	i eam ,							
Proposed 1 <sup>st</sup> Ship Date:			e: M	May 21, 2024			Sample requests accepted until:			March 22, 2024*
*Sa	mple	requests rec	eived	after	March 22	, 2024	will not	be	sup	ported.
Change Type:										
	Assen	nbly Site			Design				Wa	fer Bump Material

Mechanical Specification Test Site Packing/Shipping/Labeling Test Process

**PCN Details** 

Part number change

Data Sheet

## **Description of Change:**

**Assembly Process** 

**Assembly Materials** 

Texas Instruments is pleased to announce the qualification of its RFAB fabrication facility as an additional Wafer Fab option in addition to an Assembly site options for the devices listed

C	urrent Fab Sit	te	Additional Fab Site				
Fab Site	Process	Wafer Diameter	Fab Site	Process	Wafer Diameter		
DL-LIN	LBC3S	200 mm	RFAB	LPC7	300 mm		
CFAB	LBC3S	200 mm	KFAD	LBC7	300 111111		

The die was also changed as a result of the process change.

There are no construction differences, but only additional assembly site qualifications for some of the devices. Please see product affected section below for details.

The datasheets will be changing as a result of the above mentioned changes. The datasheet change details can be reviewed in the datasheet revision history. The link to the revised datasheet is available in the table below.



Changes from Revision M (November 2004) to Revision N (February 2024)	
	Page
Changed the Handling Ratings table to the ESD Ratings table	4
Changed the Thermal Information table	4
TEXAS	MAX202
INSTRUMENTS SLLS576G – JULY 2003 – REVISED	
Changes from Revision F (September 2016) to Revision G (February 2024)	Page
Changed the Package Information table	1
Changed the Package Information table     Changed values in the Thermal Information table	4
₹ Texas	MAX232F
IEXAS	IVIMAZOZE

Changed the Thermal Information table......5

Wafer Bump Process

Wafer Fab Material

Wafer Fab Process

Wafer Fab Site



## Changes from Revision D (March 2021) to Revision E (February 2024)



TRS202E

SLLS847F - JULY 2007 - REVISED FEBRUARY 2024

## Changes from Revision E (November 2016) to Revision F (February 2024)

- Changed the Thermal Information table.....

Product Folder	Current Datasheet Number	New Datasheet Number	Link to full datasheet
MAX232	SLLS047M	SLLS047N	http://www.ti.com/product/MAX232
MAX202	SLLS576F	SLLS576G	http://www.ti.com/product/MAX202
MAX232E	SLLS723C	SLLS723D	http://www.ti.com/product/MAX232E
TRS232E	SLLS791C	SLLS791D	http://www.ti.com/product/TRS232E
TRS202E	SLLS847E	SLLS847F	http://www.ti.com/product/TRS202E

Qual details are provided in the Qual Data Section.

## **Reason for Change:**

These changes are part of our multiyear plan to transition products from our 200-millimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

## Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

## **Impact on Environmental Ratings:**

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

RoHS	REACH	<b>Green Status</b>	IEC 62474
No Change	No Change	No Change	No Change

## Changes to product identification resulting from this PCN:

### Fab Site

## Information:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
CFAB	CU3	CHN	Chengdu
DL-LIN	DLN	USA	Dallas
RFAB	RFB	USA	Richardson

### Die Rev:

Current	New
Die Rev [2P]	Die Rev [2P]
A. B	_

## **Assembly Site Information:**

Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City
ASESH	ASH	CHN	Shanghai
TI Mexico	MEX	MEX	Aguascalientes
MLA	MLA	MYS	Kuala Lumpur

Sample product shipping label (not actual product label):





(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483812

(2P) REV: (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

## **Product Affected:**

**Group 1 Device Table (RFAB/Process migration only):** 

Oromp - Porrido rumi	- (141 7 12 / 1 1 0 0 0 0 0 1 1 1 g)	<u> </u>	
MAX202IDR	MAX232EIN	MAX232IDR	MAX232NSR
MAX202IDRE4	MAX232EINE4	MAX232IDRG4	TRS202EIPWR
MAX202IDWR	MAX232EIPWR	MAX232IDWR	TRS232EIDWR
MAX202IPWR			•

# Group 2 Device Table (RFAB/Process migration plus TI Mexico as additional Assembly site):

232DR	MAX232ECDR	MAX232EIDR	TRS202EIDR

# Group 3 Device Table (RFAB/Process migration plus TI Malaysia as additional Assembly site):

MAX232N	MAX232NE4

For alternate parts with similar or improved performance, please visit the product page on  $\overline{\text{TI.com}}$ 

#### Qualification Results

#### Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: CD4051BM96	Qual Device: CD4052BM96	Qual Device: CD4053BM96	QBS Reference (Process, Product): TMUX4051PWR	QBS Reference (Process): TPS25221DBVR	QBS Reference (Process, Product): TMUX4052PWR	QBS Reference (Package): ULQ200SAQDRQ1	QBS Reference (Package): MCS306SADR	QBS Reference (Process, Product): TMUX4051PWRQ1	QBS Reference (Process, Product): TMUX4052PWRQ1	QBS Reference (Process, Product): TMUX4053PWR
HAST	A2	Biased HAST	130C/8596RH	96 Hours		-	-		-	-	3/231/0	3/231/0	-		-
UHAST	A3	Autoclave	121C/15psig	96 Hours		-	-		-	-	3/231/0		-	-	-
UHAST	A3	Unbiased HAST	130C/8596RH	96 Hours	-	-	-		-	-	-	3/231/0	-	-	-
тс	Α4	Temperature Cycle	-65C/150C	500 Cycles			•	-	-	-	3/231/0	3/231/0	-	-	-
HTSL	A5	High Temperature Storage Life	150C	1000 Hours		-	-		-		3/135/0	-	-		-
HTSL	A6	High Temperature Storage Life	170C	420 Hours								3/231/0	-		-
HTOL	81	Life Test	140C	480 Hours	-	-	-		3/231/0	-	-	-	-	-	-
HTOL	81	Life Test	150C	300 Hours			-		-	-	-		1/77/0	-	-
ELFR	B2	Early Life Failure Rate	125C	48 Hours		-	-		3/2400/0		-	-	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-			-				1/15/0		-	-	
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-		-	-		-		1/15/0	-	-	-	
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-			-		-			
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	-	-	-	-	-	-	-	-	-	
LU	E4	Latch-Up	Per JESD78	-		-	-	1/3/0	-	-		-	1/6/0	1/6/0	1/3/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	1/30/0	-	1/30/0	-	-	1/30/0	1/30/0	1/30/0

- QBS: Qual By Similarity
- Qual Device CD4051BM96 is qualified at MSL1 260C
- Qual Device CD4052BM96 is qualified at MSL1 260C
- Qual Device CD4053BM96 is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
  The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

  The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

  The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

  The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

  The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

  The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

  The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

  The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

  The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

  The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

  The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

  The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

  The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

  The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/1k Hours in the following the f
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

TI Qualification ID: R-CHG-2110-063

### Qualification Results

#### Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: CD4051BNSR	Qual Device: CD4052BNSR	Qual Device: CD4053BNSR	QBS Reference (Package): TL092CPS	QBS Reference (Package): SN75ALS1177NS	QBS Reference (Process, Product): TMUX4053PWR	QBS Reference (Package, Process): AM26LS32ACN	QBS Reference (Process, Product): TMUX4051PWRQ1	QBS Reference (Process, Product): TMUX4052PWRQ1
UHAST	А3	Autoclave	121C/15psig	96 Hours	-	-	-	3/230/0	3/231/0		-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles		-		3/231/0	3/231/0	-	-	-	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	3/231/0	-	-	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	-	-	-	1/77/0	-
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	-	-	-	-	-	1/76/0	1/76/0	-	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	-	-	-	-	-	1/76/0	1/76/0	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	-	-	-	-	-	-
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	-	-	-	-	-	-	-	-
LU	E4	Latch-Up	Per JESD78	-	-	-	-	-	-	-	-	1/6/0	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/10/0	1/10/0	1/10/0	-	-	-	-	-	-
FTY	E6	Final Test Yield	-	-	-	-	-	-	-	-	1/1/0	-	-

- QBS: Qual By Similarity
   Qual Device CD4051BNSR is qualified at MSL1 260C
- Qual Device CD4052BNSR is qualified at MSL1 260C
   Qual Device CD4053BNSR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
   The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
   The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

TI Qualification ID: R-CHG-2308-005

#### **Oualification Results**

#### Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: CD4051BE	Qual Device: CD4052BE	Qual Device: CD4053BE	QBS Reference (Package): SN74HC595N	QBS Reference (Package, Process, Product): TPS25221DBVR	QBS Reference (Package, Process): AM26LS32ACN	QBS Reference (Process, Product): TMUX4051PWRQ1	QBS Reference (Process, Product): TMUX4052PWRQ1	QBS Reference (Process, Product): TMUX4053PWR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	3/231/0	-	-	-	-
UHAST	А3	Autoclave	121C/15psig	96 Hours	-	-	-	3/231/0	-	-	-	-	-
UHAST	А3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	3/231/0	-	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles		-	-	3/231/0	3/231/0	-	-	-	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours		-	-	3/231/0	3/231/0	-	-	-	-
HTOL	B1	Life Test	140C	480 Hours	-	-	-	-	3/231/0	-	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	-	-	1/77/0	-	-
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	-	-	3/2400/0	-	-	-	-
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	-	-	-	-	3/9/0	1/76/0	-	-	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	-	-	-	-	3/9/0	1/76/0	-	-	-
SD	C3	PB-Free Solderability	8 Hours Steam Age	-	-	-	-	3/66/0	-	-	-	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	-	-	-	-	-	-
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	-	-	-	-	-	-	-	-

Туре		Test Name	Condition	Duration	Qual Device: CD4051BE	Qual Device: CD4052BE	Qual Device: CD4053BE	QBS Reference (Package): SN74HC595N	QBS Reference (Package, Process, Product): TPS25221DBVR	QBS Reference (Package, Process): AM26LS32ACN	QBS Reference (Process, Product): TMUX4051PWRQ1	QBS Reference (Process, Product): TMUX4052PWRQ1	QBS Reference (Process, Product): TMUX4053PWR
LU	E4	Latch-Up	Per JESD78	-	-	-	-	-	-	-	1/6/0	1/6/0	1/3/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/10/0	1/10/0	1/10/0	-	-	-	-	-	-
FTY	E6	Final Test Yield	-	-	-	-	-	-		1/1/0	-	-	

- QBS: Qual By Similarity
  Qual Device CD4051BE is qualified at MSL1 260C
  Qual Device CD4052BE is qualified at MSL1 260C
  Qual Device CD4053BE is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/Ik Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
   The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

TI Qualification ID: R-CHG-2307-070

#### **Qualification Results**

Туре	#	Test Name	Condition	Duration	Qual Device: TRS202EIDR	QBS Reference (Process): TPS51217DSCR	QBS Reference (Package): ULQ2003AQDRQ1	QBS Reference (Package, Process Product): MAX232EIDR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	3/231/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	3/231/0	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	3/135/0	-
HTOL	B1	Life Test	135C	635 Hours	-	3/231/0	-	-
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	-	-	-	1/76/0
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	-	-	-	1/76/0
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-

Туре	#	Test Name	Condition	Duration	Qual Device: IRS202EIDR	QBS Reference (Process): TPS51217DSCR	QBS Reference (Package): <u>ULQ2003AQDRQ1</u>	QBS Reference (Package, Process Product): MAX232EIDR
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-
ESD	E2	ESD CDM	-	1500 Volts	1/3/0	-	-	-
ESD	E2	ESD HBM (Bus Pins)	-	15000 Volts	-	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	1/3/0	-	-	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	-

- QBS: Qual By Similarity
- Qual Device TRS202EIDR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
   The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

TI Qualification ID: R-CHG-2302-013

#### Qualification Results

Туре	#	Test Name	Condition	Duration	Qual Device: MAX232EIPWR	Qual Device: MAX232NSR	Qual Device: TRS202EIPWR	Qual Device: MAX232EIN	QBS Reference (Package): SN74HC595N	QBS Reference (Process): TPS51217DSCR	QBS Reference (Package): SN74LVC8T245NSR	QBS Reference (Package): OPA4992QPWRQ1	QBS Reference (Package, Process, Product): MAX232EIDR
HAST	A2	Biased HAST	110C/85%RH	264 Hours	-		-	-	-	-	-	1/77/0	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	3/231/0	-	-	-
UHAST	А3	Autoclave	121C/15psig	96 Hours	-	-	-	-	3/231/0	-	-	-	-
UHAST	А3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	1/77/0	-
тс	A4	Temperature Cycle	-65C/150C	500 Cycles	-		-	-	3/231/0	-	3/231/0	1/77/0	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	-	-	3/231/0	-	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	-	3/231/0	-	-		-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	-	-	1/77/0	-
HTOL	B1	Life Test	135C	635 Hours	-	-	-	-	-	3/231/0	-	-	-
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	-		-	-	-	-	-	-	1/76/0
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	-	-	-	-	-	-	-	-	1/76/0
SD	C3	PB-Free Solderability	8 Hours Steam Age	-	-	-	-	-	3/66/0	-	-	-	-

Туре	#	Test Name	Condition	Duration	Qual Device: MAX232EIPWR	Qual Device: MAX232NSR	Qual Device: TRS202EIPWR	Qual Device: MAX232EIN	QBS Reference (Package): SN74HC595N	QBS Reference (Process): TPS51217DSCR	QBS Reference (Package): SN74LVC8T245NSR	QBS Reference (Package): <u>OPA4992QPWRQ1</u>	QBS Reference (Package, Process, Product): MAX232EIDR
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	-	-	-	-	1/10/0	-
ESD	E2	ESD CDM		1000 Volts	-	1/3/0	-	-	-	-	-	-	-
ESD	E2	ESD CDM		1500 Volts	1/3/0		1/3/0	1/3/0	-	-	-	-	1/3/0
ESD	E2	ESD HBM (Bus Pins)		15000 Volts	-		-	-	-	-	-	-	1/3/0
ESD	E2	ESD HBM		2000 Volts	-	1/3/0	-	-	-	-	-	-	-
ESD	E2	ESD HBM		3000 Volts	1/3/0		-	1/3/0	-	-	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	-	-	-	-	-	-	1/3/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	1/30/0	-	-	-	-	1/30/0

- QBS: Qual By Similarity
   Qual Device MAX232EIPWR is qualified at MSL1 260C

- Qual Device MAX232NSR is qualified at MSL1 260C
  Qual Device TRS202EIPWR is qualified at MSL1 260C
  Qual Device MAX232EIN is qualified at MOT CLASSIFIED NOT CLASSIFIED
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
  The following are equivalent HTOL options based on an activation energy of 0.7eV: 1250/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
  The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
  The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

TI Qualification ID: R-CHG-2302-014

#### **Qualification Results**

Туре	#	Test Name	Condition	Duration	Qual Device: MAX202IDWR	Qual Device: TRS232EIDWR	QBS Reference (Process): TPS51217DSCR	QBS Reference (Package): TLC59116ПPWRQ1	QBS Reference (Package): <u>TPIC6A596DW</u>	QBS Reference (Package, Process, Product): MAX232EIDR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	3/231/0	-
UHAST	АЗ	Autoclave	121C/15psig	96 Hours	-	-	-	3/231/0	-	-
UHAST	А3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	3/231/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	3/231/0	3/231/0	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	3/135/0	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	1/45/0	-	-
HTOL	B1	Life Test	135C	635 Hours	-	-	3/231/0	-	-	-

Туре	#	Test Name	Condition	Duration	Qual Device: MAX202IDWR	Qual Device: TRS232EIDWR	QBS Reference (Process): IPS51217DSCR	QBS Reference (Package): TLC59116IIPWRQ1	QBS Reference (Package): <u>TPIC6A596DW</u>	QBS Reference (Package, Process, Product): MAX232EIDR
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	-	-	-	-	-	1/76/0
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	-	-	-	-	-	1/76/0
ESD	E2	ESD CDM	-	1000 Volts	-	1/3/0	-	-	-	-
ESD	E2	ESD CDM	-	1500 Volts	1/3/0	-	-	-	-	-
ESD	E2	ESD HBM (Bus Pins)	-	15000 Volts	-	-	-	-	-	1/3/0
ESD	E2	ESD HBM	-	3000 Volts	-	1/3/0	-	-	-	-
LU	E4	Latch-Up	Per JESD78	-	-	-	-	-	-	1/3/0
CHAR	<b>E</b> 5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	-	-	-	1/30/0

- QBS: Qual By Similarity
- Qual Device MAX202IDWR is qualified at MSL1 260C
- Qual Device TRS232EIDWR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
   The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

TI Qualification ID: R-CHG-2302-015

#### **Qualification Results**

Туре	#	Test Name	Condition	Duration	Qual Device: MAX232EIDR	QBS Reference (Process): TPS51217DSCR	QBS Reference (Package): <u>ULQ2003AQDRQ1</u>	QBS Reference (Product, Package): MAX232DR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	3/231/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	3/231/0	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	3/231/0	3/231/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	3/135/0	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	3/231/0
HTOL	B1	Life Test	135C	635 Hours	-	3/231/0	-	-
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	1/76/0	-	-	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	1/76/0	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-

Туре	#	Test Name	Condition	Duration	Qual Device: MAX232EIDR	QBS Reference (Process): TPS51217DSCR	QBS Reference (Package): ULQ2003AQDRQ1	QBS Reference (Product, Package): <u>MAX232DR</u>
ESD	E2	ESD CDM	-	1500 Volts	1/3/0	-	-	-
ESD	E2	ESD HBM (Bus Pins)	-	15000 Volts	1/3/0	-	-	-
ESD	E2	ESD HBM	-	3000 Volts	1/3/0	-	-	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	-	-	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	-

- . OBS: Oual By Similarity
- Qual Device MAX232EIDR is qualified at MSL1 260C
- . Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

TI Oualification ID: R-CHG-2302-012

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